TOSHIBA

TOSHIBA THYRISITOR SILICON PLANAR TYPE

RSF05G1-1P,RSF05G1-3P,RSF05G1-5P

LOW POWER SWITCHING AND CONTROL APPLICATIONS

• Repetitive Peak Off-State Voltage : V_{DRM} = 400V Repetitive Peak Reverse Voltage $: V_{RRM} = 400V$ $: I_{T (AV)} = 500 \text{mA}$ • Average On-State Current

Plastic Mold Type

Reduce a Quantity of Parts and Manufacturing

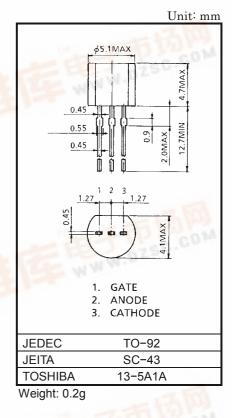
Process Because of Built-in RGK $: R_{GK} = 1k\Omega, 2.7k\Omega, 5.1k\Omega$

(Typical)

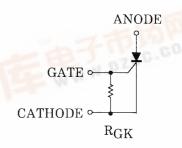
MAXIMUM RATINGS

CHARACTER	ISTIC	SYMBOL	RATING	UNIT	
Repetitive Peak	RSF05G1-1P		400	V	
Off-State Voltage and Repetitive Peak Reverse Voltage	RSF05G1-3P	V_DRM V_RRM	400		
	RSF05G1-5P		400		
Non-Repetitive Peak Reverse Voltage (Non-Repetitive< 5ms, Tj = 0~125°C)	RSF05G1-1P	T-12-12	500	V	
	RSF05G1-3P	V _{DSM}	500		
	RSF05G1-5P		500		
Average On-State Cur (Half Sine Waveform)	rent	$I_{T(AV)}$	500	mA	
R.M.S. On-State Curre	ent	I _{T(RMS)}	800	mA	
Peak One Cycle Surge On-State Current (Non-Repetitive)		I _{TSM}	9 (50Hz)	А	
			10 (60Hz)		
I ² t Limit Value		I ² t	0.4	A ² s	
Critical Rate of Rise of Current	On-State	di / dt	10	A / μs	
Peak Gate Power Dissipation		P _{GM}	0.1	W	
Average Gate Power D	<mark>issipa</mark> tion	P _{G(AV)}	0.01	W	
Peak Forward Gate Vo	ltage	V_{FGM}	3.5	V	
Peak Reverse Gate Vo	Itage	V_{RGM}	-5	V	
Peak Forward Gate Cu	rrent	I _{GM}	125	mA	
Junction Temperature		Tj	-40~125	°C	
Storage Temperature		T _{stg}	-40~12 <mark>5</mark>	°C	

di / dt Test Condition, i $_G$ = 5mA, t_{gw} = 10 μ s, t_{gr} \leq 250ns WWW.DZSC.C



EQUIVALENT CIRCUIT





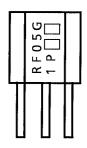


ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT	
Repetitive Peak Off-State Current and Repetitive Peak Reverse Current		I _{DRM} I _{RRM}	V _{DRM} = V _{RRM} = Rated	_	_	10	μА	
Peak On-State Voltage		V _{TM}	I _{TM} = 1A	_	_	1.5	V	
Gate Trigger Voltage		V _{GT}		0.4	_	8.0	V	
Gate Trigger Current		RSF05G1-1P) 	400	700	1000	
	RSF05G1-3P	I _{GT}	$V_D = 6V, R_L = 100\Omega$	150	250	400	μΑ	
	RSF05G1-5P			80	160	250		
Holding Current		RSF05G1-1P			_	_	6	
	RSF05G1-3P	lн	$I_{TM} = 1A$, $V_D = 6V$	_	_	3	mA	
	RSF05G1-5P			_	_	2		
Resistor Between Gate and Cathode		RSF05G1-1P			700	1000	1300	
	RSF05G1-3P	R _{GK}	_	1890	2700	3510	Ω	
	RSF05G1-5P			3570	5100	6630		
Critical Rate of Rise of Off-State Voltage	RSF05G1-1P			_	200	_		
		RSF05G1-3P	dv / dt	V _{DRM} = Rated Exponential Rise	_	70	_	V/µs
		RSF05G1-5P			_	40	_	
Gate Turn-On Time		t _{gt}	V _D = Rated, i _G = 5mA	_	_	1.5	μs	
Posistanas	Junction to Lead Junction to Ambient		R _{th(j −ℓ)}	-DC	_	_	40	°C/W
			R _{th(j−a)}		_	_	180	

MARKING

Example: It is mark of RSF05G1-1P

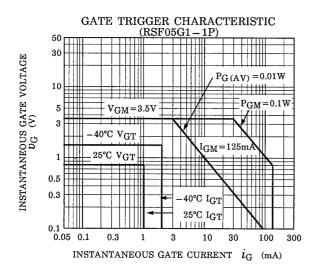


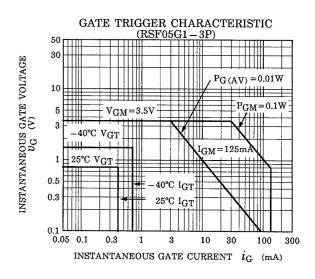
Lot Number

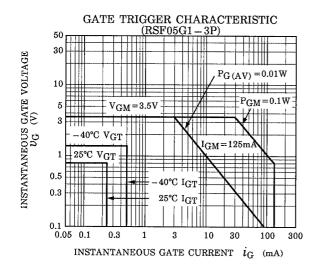
| _____ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | ___ | __

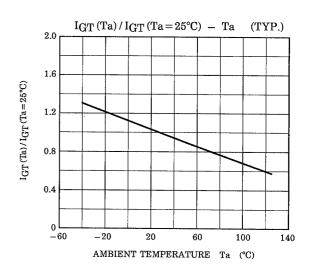
Example 8A: January 1998

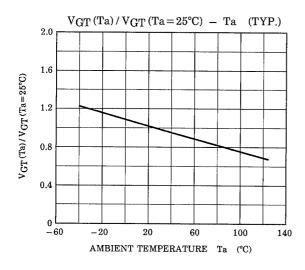
8B: Febrary 1998 8L: December 1998

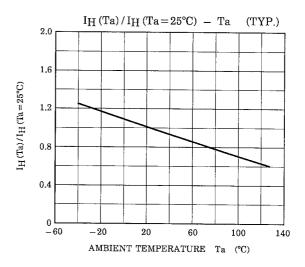


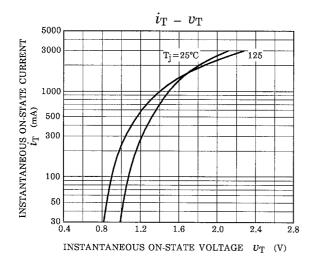


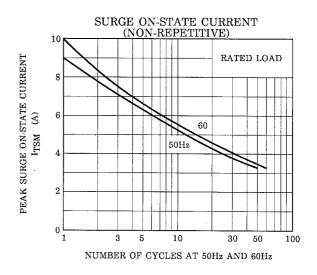


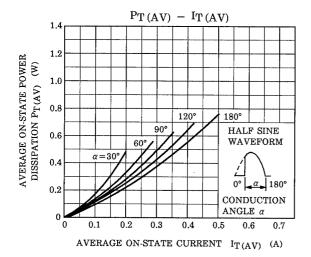


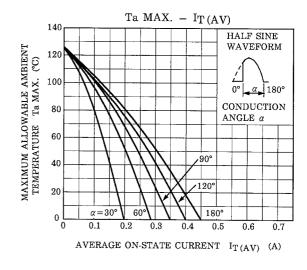


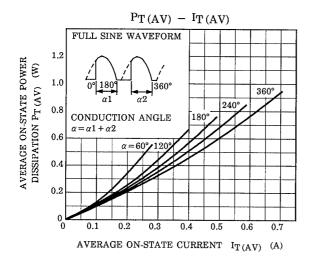


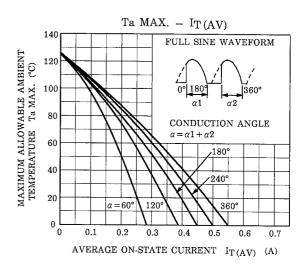


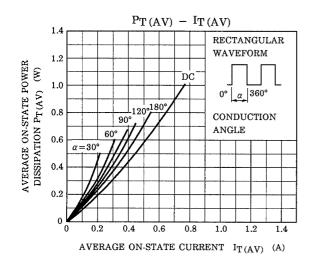


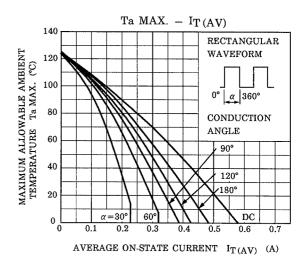


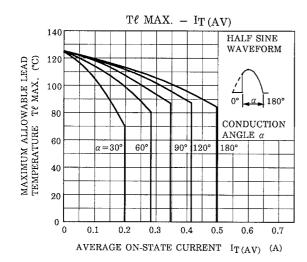


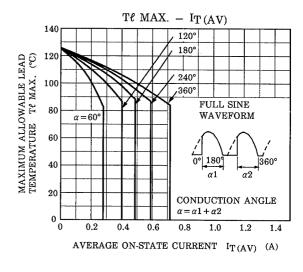


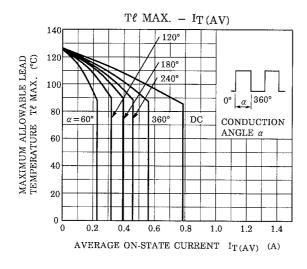


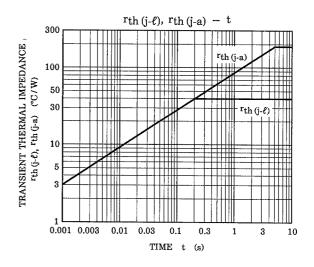












5

RESTRICTIONS ON PRODUCT USE

000707EA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The information contained herein is presented only as a guide for the applications of our products. No
 responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other
 rights of the third parties which may result from its use. No license is granted by implication or otherwise under
 any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.